



# P-Channel Enhancement Mode Field Effect Transistor



## **General Description**

The AO4459 uses advanced trench technology to provide excellent R<sub>DS(ON)</sub> with low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard product AO4459 is Pb-free (meets ROHS & Sony 259 specifications). AO4459L is a Green Product ordering option. AO4459 and AO4459L are electrically identical.

### **Features**

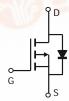
 $V_{DS}(V) = -30V$ 

 $I_D = -6.5A$   $(V_{GS} = -10V)$ 

 $R_{DS(ON)}$  < 46m $\Omega$  ( $V_{GS}$  = -10V)

 $R_{DS(ON)} < 72m\Omega (V_{GS} = -4.5V)$ 





Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		$V_{DS}$	-30	V			
Gate-Source Voltage		V <sub>GS</sub>	±20	V			
Continuous Drain	T <sub>A</sub> =25°C	150.0	-6.5				
Current <sup>A</sup>	T <sub>A</sub> =70°C	I <sub>D</sub>	-5.3	Α			
Pulsed Drain Current B		I <sub>DM</sub>	-30				
T WILL THE	T <sub>A</sub> =25°C	D	3.1	W			
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70°C	$-P_{D}$	2				
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150	°C			

Thermal Characteristics								
Parameter	Symbol Typ Max			Units				
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta JA}$	33	40	°C/W			
Maximum Junction-to-Ambient A	Steady-State	θЈА	62	75	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	18	24	°C/W			

## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Parameter Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$		-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =-24V, $V_{GS}$ =0V $T_{J}$ =55°C				-1	μА
	Zero Gate Voltage Drain Guirent					-5	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=-250 \mu A$		-1.5	-1.85	-2.5	V
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V		-30			Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.5A			38	46	mΩ
			T <sub>J</sub> =125°C		53	68	11122
		$V_{GS}$ =-4.5V, $I_{D}$ =-5A			58	72	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =-5V, $I_{D}$ =-6.5A			11		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =-1A,V <sub>GS</sub> =0V			-0.78	-1	V
Is	Maximum Body-Diode Continuous Current					-3.5	Α
DYNAMIC	PARAMETERS						
$C_{\text{iss}}$	Input Capacitance				668	830	pF
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =-15V, f=1MHz			126		pF
$C_{rss}$	Reverse Transfer Capacitance				92		pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			6	9	Ω
SWITCHI	NG PARAMETERS	•	•		•	•	•
Q <sub>g</sub> (10V)	Total Gate Charge (10V)				12.7	16	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)	V10V V15V	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-6.5A		6.4		nC
$Q_{gs}$	Gate Source Charge	- V <sub>GS</sub> =-10V, V <sub>DS</sub> =-13V, I <sub>D</sub> =-0.3A			2		nC
$Q_{gd}$	Gate Drain Charge				4		nC
t <sub>D(on)</sub>	Turn-On DelayTime				7.7		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =-10V, $V_{DS}$ =-15V, $R_L$ =2.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			6.8		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				20		ns
t <sub>f</sub>	Turn-Off Fall Time				10		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6.5A, dI/dt=100A/	μS		22	30	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-6.5A, dI/dt=100A/	μS		15		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10$ s thermal resistance rating.

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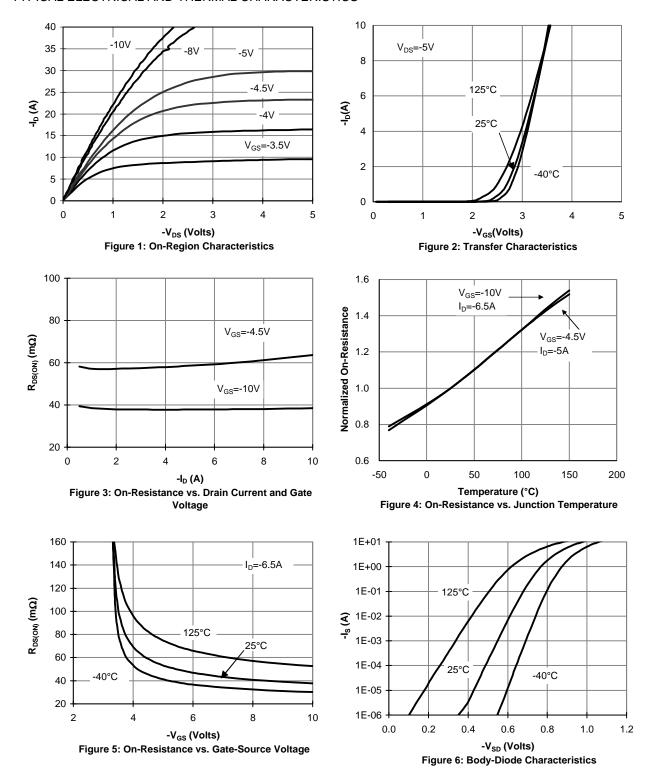
B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta,IA}$  is the sum of the thermal impedence from junction to lead  $R_{\theta,IL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using < 300 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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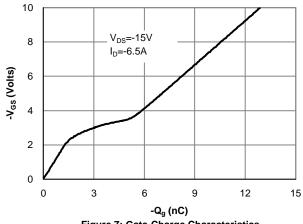


Figure 7: Gate-Charge Characteristics

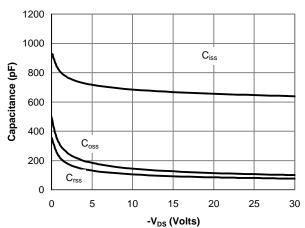


Figure 8: Capacitance Characteristics

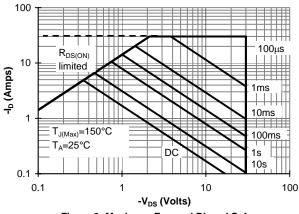


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

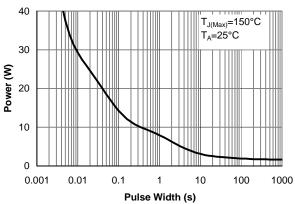


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

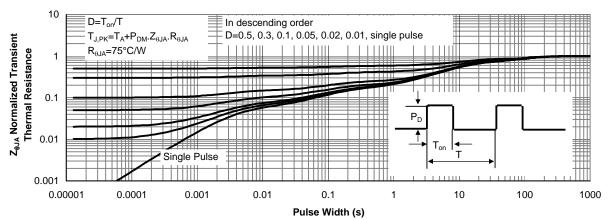


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)